

**IEEE1647 e language standards group Committee  
call for participation**

Individuals interested in functional verification languages are hereby invited to take part in the 1647 working group effort. This effort is aimed at standardizing the **e** functional verification language. The **e** language has been evolving since its introduction in 1996, and is used today by a large community of industrial and academic users.

We are currently working towards the P1647-2010 revision of the standard and the following widely used language features are part of this effort:

- \* Define-As-Computed
- \* Interface Ports
- \* Named Constraints
- \* Parameterized Types
- \* Real Data Type
- \* Temporal Coverage
- \* Type Constraints

Anybody with any interest in the **e** language could effect changes in the upcoming revision which could be of benefit to you. Consequently, I'm calling on new participants to help push this language forward by joining the IEEE Working Group for the **e** language yourself, or/and inviting any interested parties.

The good news is that it's very easy to participate: simply dial-in to an hour-long conference call once a month via a toll-free number setup for your home country. You can dive in and contribute to the discussion, or sit back and quietly monitor the group's progress. Alternatively, a single message posted to the IEEE 1647 working group email reflector on a topic recorded in the minutes of the previous meeting is sufficient to qualify the author as attending the associated meeting. Either way, you will be able to ensure you & your company's needs will be captured in the standard.

The next working group meeting will be posted on the website and I welcome you or/and a colleague to dial-in to get a feel for the Group. The agenda, along with a list of world-wide toll free dial-in numbers, is posted here: <http://iee1647.org/agenda.html>

If you want to join, please submit your details on <http://iee1647.org/join.html>

And please let me know if you have any further questions.

Warm Regards,

Serrie Chapman  
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